Contents

APPENDIX

1. Photographs of Test Setup

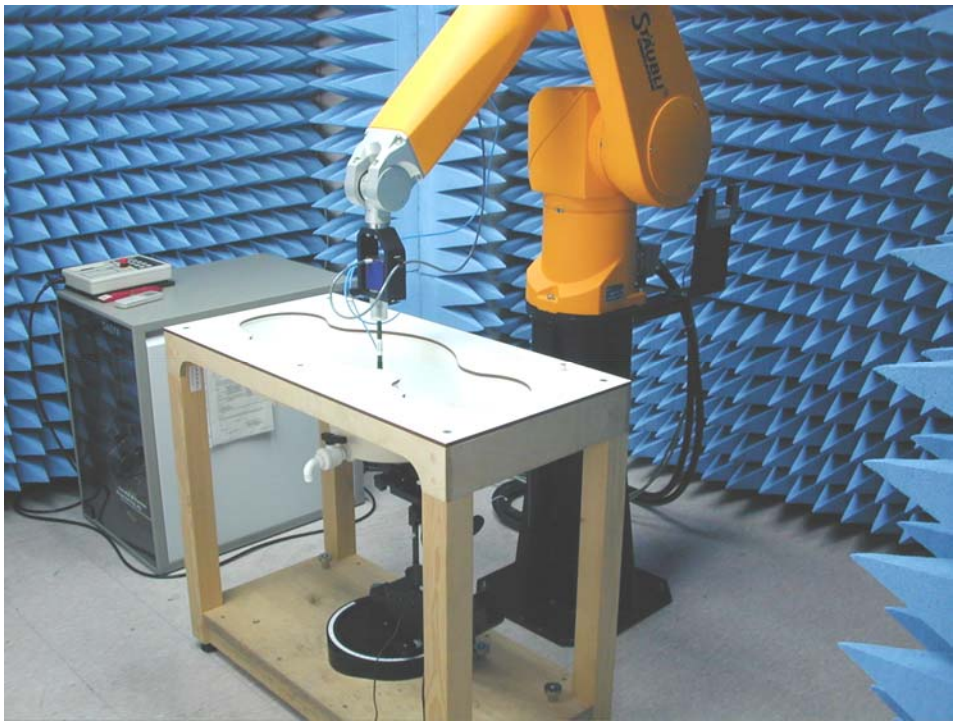

Fig.1 Photograph of the SAR measurement System

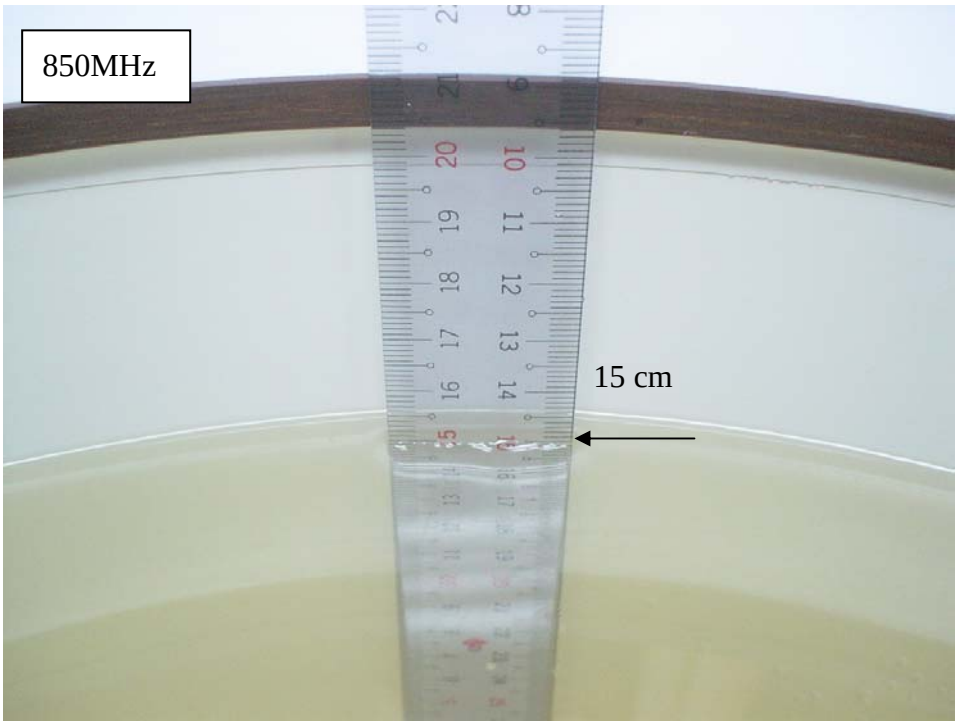

Fig.2.1 Photograph of the Tissue Simulant liquid depth 15cm for Flat position

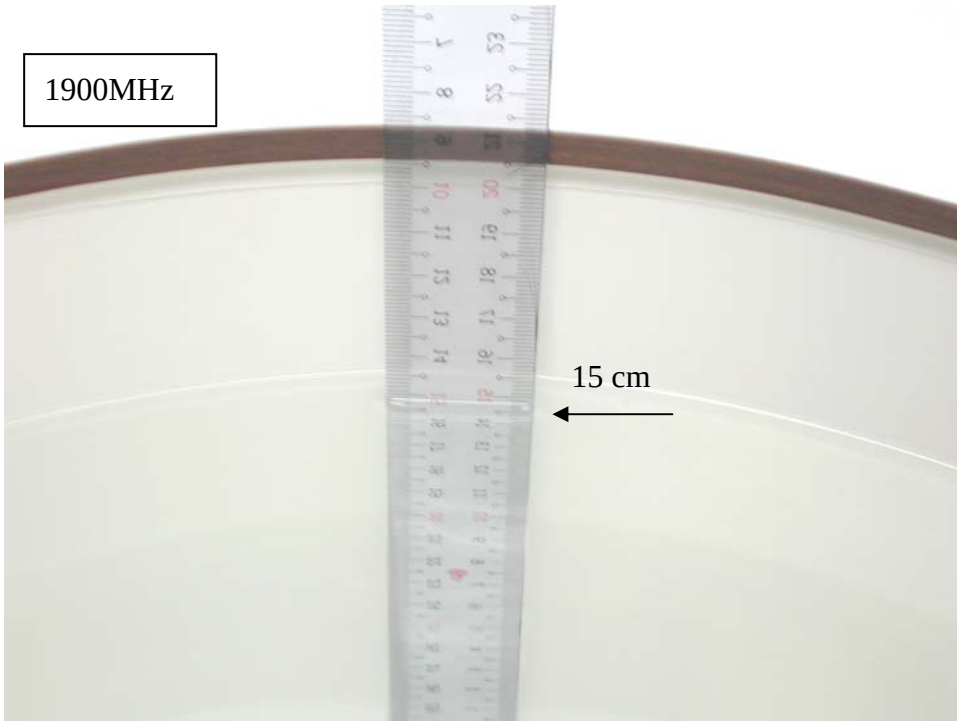

Fig.2.2 Photograph of the Tissue Simulant liquid depth 15cm for Flat position

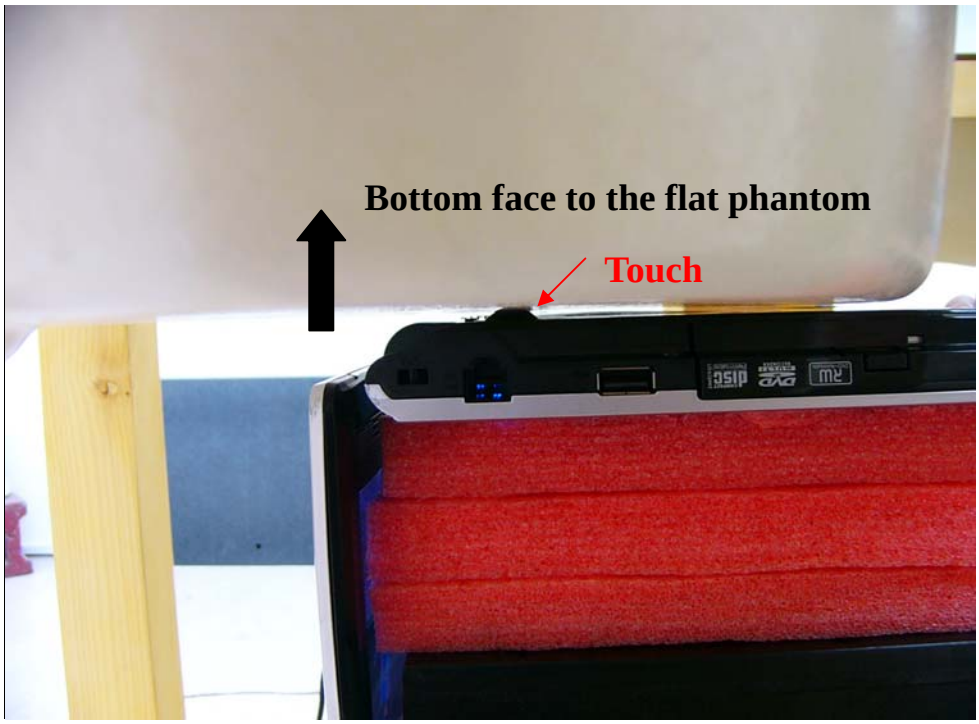

Fig.3 Photo of the Bottom face of the notebook is paralleled with flat phantom,

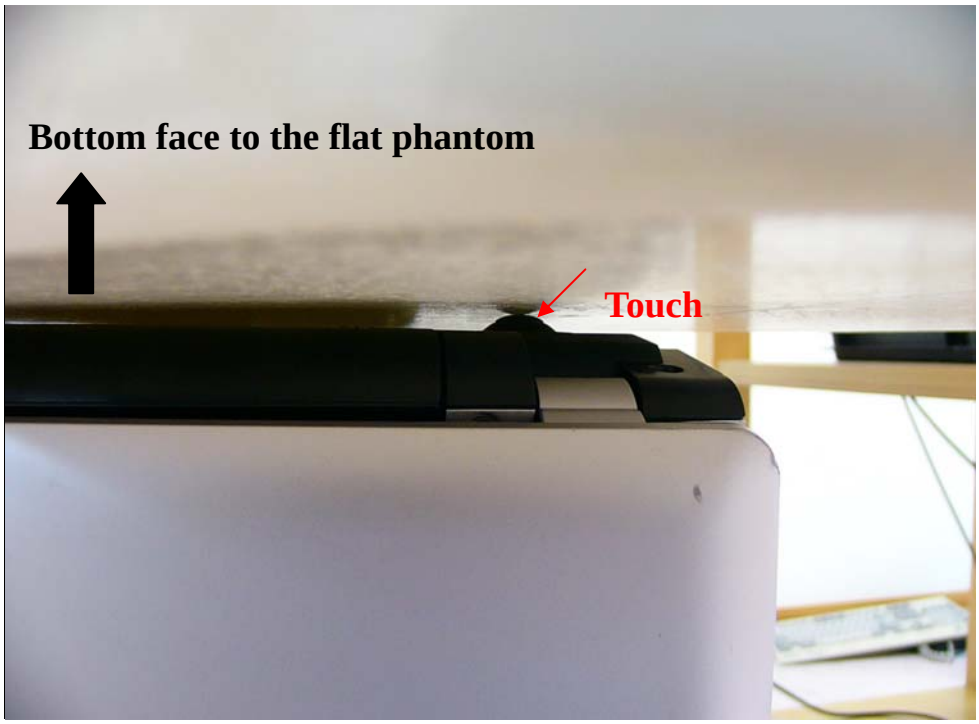

Fig.4 Photo of the Bottom face of the notebook is paralleled with flat Phantom

Fig.5 Photo of the right side of the LCD of Notebook is vertical with flat phantom and spacing between EUT and Phantom- in contact 15mm.

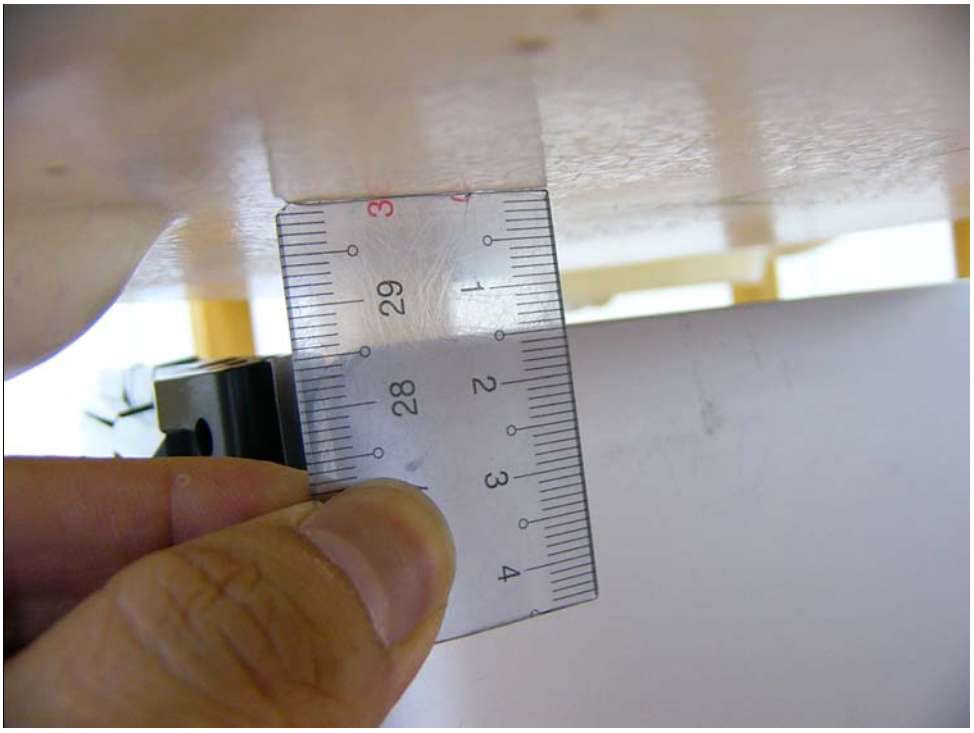

Fig.6 Photo of the right side of the LCD of Notebook is vertical with flat phantom and spacing between EUT and Phantom- in contact 15mm.

2. Photographs of the EUT

Fig.7 Front view of EUT

Fig.8 Back view of EUT

Fig.9 Left Side of EUT

Fig.10 Right Side of EUT

Fig.11 Fold up of EUT

3. Photographs of the Accessories of EUT

Fig.12 Notebook charger

4. DAE & Probe Calibration certificate

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland

S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Client **SGS (Auden)**

Certificate No: DAE4-547_Mar07

CALIBRATION CERTIFICATE

Object	DAE4 - SD 000 D04 BA - SN: 547
Calibration procedure(s)	QA CAL-06.v12 Calibration procedure for the data acquisition electronics (DAE)
Calibration date:	March 5, 2007
Condition of the calibrated item	In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Fluke Process Calibrator Type 702	SN: 6295803	13-Oct-06 (Elcal AG, No: 5492)	Oct-07
Keithley Multimeter Type 2001	SN: 0810278	03-Oct-06 (Elcal AG, No: 5478)	Oct-07
Secondary Standards	**ID #**	**Check Date (in house)**	**Scheduled Check**
Calibrator Box V1.1	SE UMS 006 AB 1002	15-Jun-06 (SPEAG, in house check)	In house check Jun-07

	Name	Function	Signature
Calibrated by:	Daniel Steinacher	Technician	
Approved by:	Fin Bomholt	R&D Director	

Issued: March 5, 2007

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland

S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Client SGS (Auden)

Certificate No: EX3-3526_Aug06

CALIBRATION CERTIFICATE

Object	EX3DV3 - SN:3526
Calibration procedure(s)	QA CAL-01.v5 and QA CAL-14.v3 Calibration procedure for dosimetric E-field probes
Calibration date:	August 25, 2006
Condition of the calibrated item	In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	5-Apr-06 (METAS, No. 251-00557)	Apr-07
Power sensor E4412A	MY41495277	5-Apr-06 (METAS, No. 251-00557)	Apr-07
Power sensor E4412A	MY41498087	5-Apr-06 (METAS, No. 251-00557)	Apr-07
Reference 3 dB Attenuator	SN: S5054 (3c)	10-Aug-06 (METAS, No. 217-00592)	Aug-07
Reference 20 dB Attenuator	SN: S5086 (20b)	4-Apr-06 (METAS, No. 251-00558)	Apr-07
Reference 30 dB Attenuator	SN: S5129 (30b)	10-Aug-06 (METAS, No. 217-00593)	Aug-07
Reference Probe ES3DV2	SN: 3013	2-Jan-06 (SPEAG, No. ES3-3013_Jan06)	Jan-07
DAE4	SN: 654	21-Jun-06 (SPEAG, No. DAE4-654_Jun06)	Jun-07

Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (SPEAG, in house check Nov-05)	In house check: Nov-07
Network Analyzer HP 8753E	US37390585	18-Oct-01 (SPEAG, in house check Nov-05)	In house check: Nov 06

	Name	Function	Signature
Calibrated by:	Katja Pokovic	Technical Manager	
Approved by:	Niels Kuster	Quality Manager	

Issued: August 26, 2006

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland

S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
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Accredited by the Swiss Federal Office of Metrology and Accreditation
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Accreditation No.: SCS 108

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., ϑ = 0 is normal to probe axis

Calibration is Performed According to the Following Standards:

a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
b) CENELEC EN 50361, "Basic standard for the measurement of Specific Absorption Rate related to human exposure to electromagnetic fields from mobile phones (300 MHz - 3 GHz), July 2001

Methods Applied and Interpretation of Parameters:

- *NORMx,y,z:* Assessed for E-field polarization ϑ = 0 (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E^2-field uncertainty inside TSL (see below *ConvF*).
- *NORM(f)x,y,z = NORMx,y,z * frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- *DCPx,y,z:* DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- *ConvF and Boundary Effect Parameters:* Assessed in flat phantom using E-field (or Temperature Transfer Standard for f ≤ 800 MHz) and inside waveguide using analytical field distributions based on power measurements for f > 800 MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to *NORMx,y,z * ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- *Spherical isotropy (3D deviation from isotropy)*: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- *Sensor Offset*: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV3

SN:3526

Manufactured:	March 19, 2004
Last calibrated:	May 24, 2004
Recalibrated:	August 25, 2006

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

EX3DV3 SN:3526 **August 25, 2006**

DASY - Parameters of Probe: EX3DV3 SN:3526

Sensitivity in Free Space[A] Diode Compression[B]

NormX	**0.92** ± 10.1%	$\mu V/(V/m)^2$	DCP X	**95** mV
NormY	**0.87** ± 10.1%	$\mu V/(V/m)^2$	DCP Y	**92** mV
NormZ	**0.85** ± 10.1%	$\mu V/(V/m)^2$	DCP Z	**94** mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL **900 MHz** **Typical SAR gradient: 5 % per mm**

Sensor Center to Phantom Surface Distance		**3.7 mm**	**4.7 mm**
SAR_{be} [%]	Without Correction Algorithm	2.1	0.9
SAR_{be} [%]	With Correction Algorithm	0.1	0.1

TSL **1810 MHz** **Typical SAR gradient: 10 % per mm**

Sensor Center to Phantom Surface Distance		**3.7 mm**	**4.7 mm**
SAR_{be} [%]	Without Correction Algorithm	1.5	0.8
SAR_{be} [%]	With Correction Algorithm	0.1	0.6

Sensor Offset

Probe Tip to Sensor Center	**1** mm

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

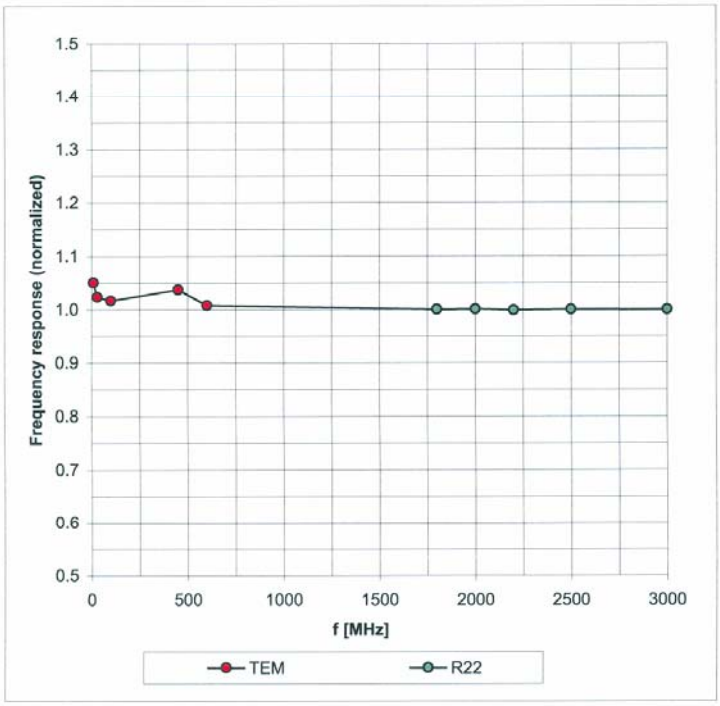
[A] The uncertainties of NormX,Y,Z do not affect the E^2-field uncertainty inside TSL (see Page 8).

[B] Numerical linearization parameter: uncertainty not required.

EX3DV3 SN:3526 August 25, 2006

Frequency Response of E-Field

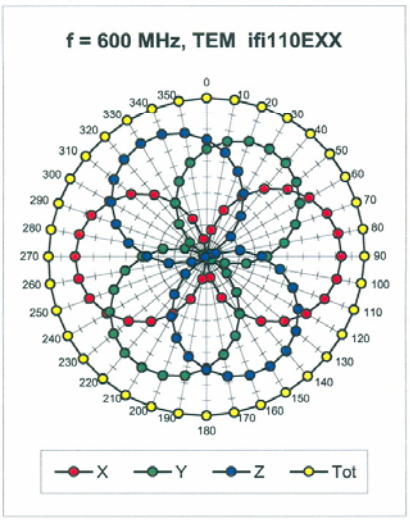
(TEM-Cell:ifi110 EXX, Waveguide: R22)

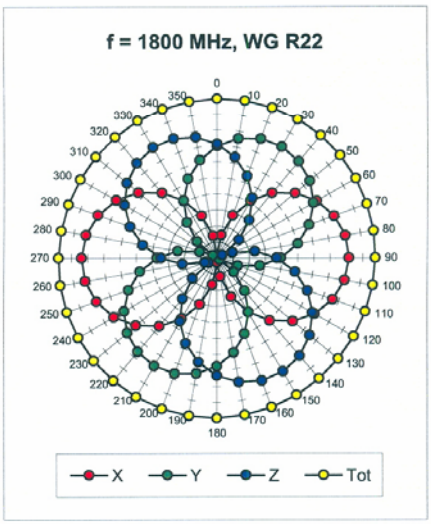


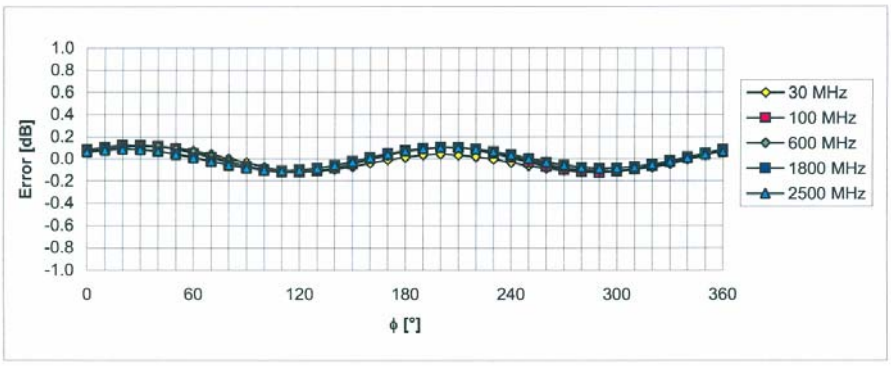
Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

EX3DV3 SN:3526 **August 25, 2006**

Receiving Pattern (ϕ), ϑ = 0°





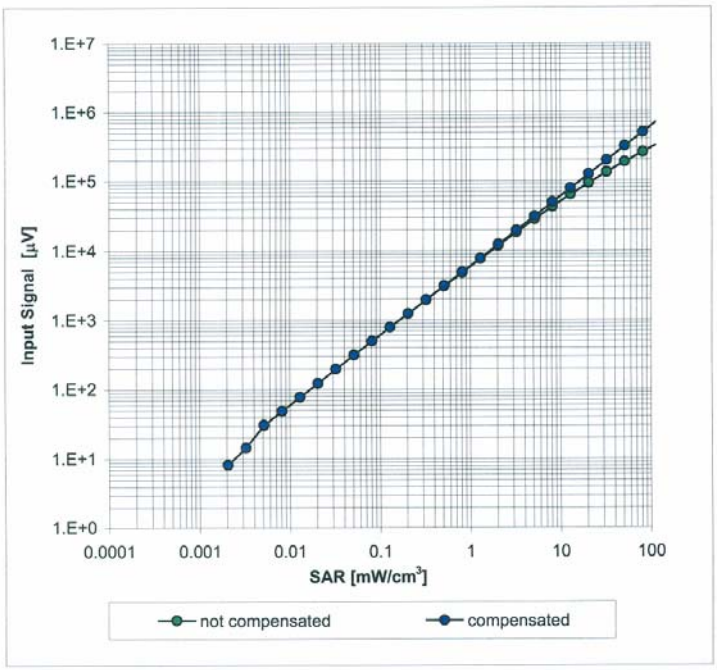


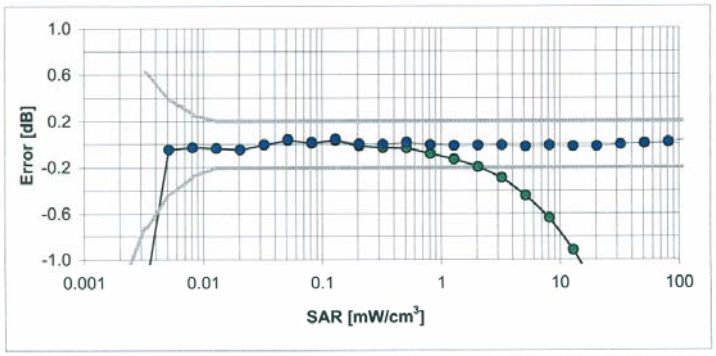
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

EX3DV3 SN:3526 August 25, 2006

Dynamic Range f(SAR_{head})

(Waveguide R22, f = 1800 MHz)

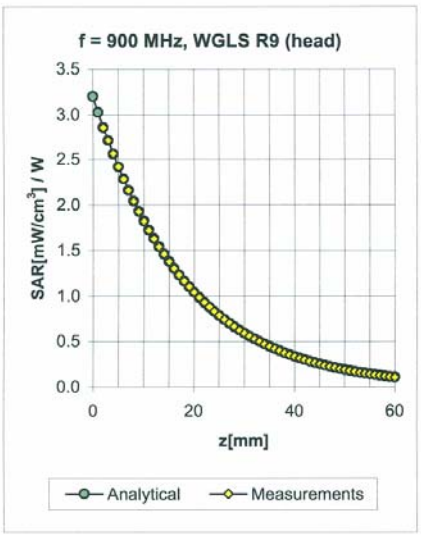


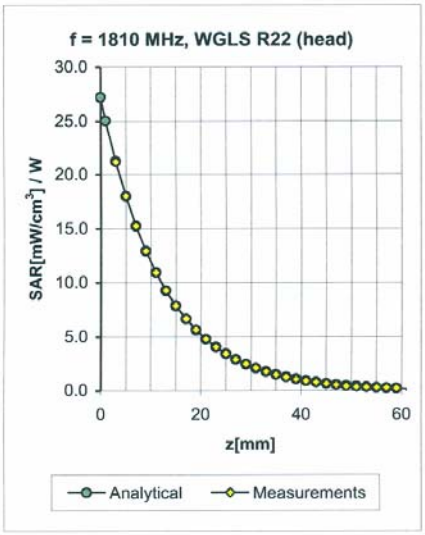


Uncertainty of Linearity Assessment: ± 0.6% (k=2)

EX3DV3 SN:3526 **August 25, 2006**

Conversion Factor Assessment





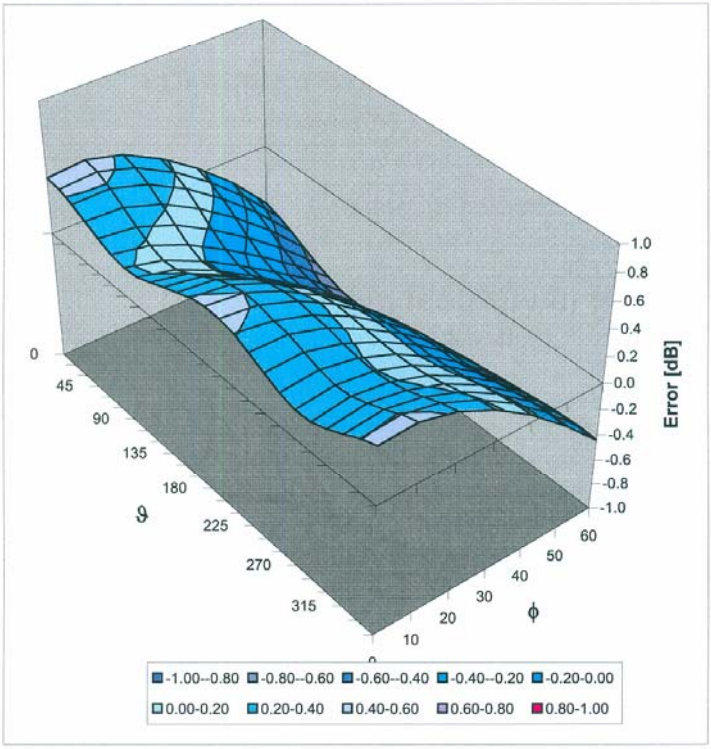
f [MHz]	Validity [MHz][C]	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.21	0.90	11.72 ± 11.0% (k=2)
1810	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.11	1.33	9.61 ± 11.0% (k=2)
1950	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.11	1.33	9.32 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.42	0.80	8.29 ± 11.8% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.21	0.89	11.63 ± 11.0% (k=2)
1810	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.19	1.32	9.64 ± 11.0% (k=2)
1950	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.15	1.55	9.26 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.40	0.52	8.30 ± 11.8% (k=2)
5200	± 50 / ± 100	Body	49.0 ± 5%	5.30 ± 5%	0.45	1.85	3.17 ± 13.1% (k=2)
5800	± 50 / ± 100	Body	48.2 ± 5%	6.00 ± 5%	0.25	1.85	2.66 ± 13.1% (k=2)

[C] **The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.**

EX3DV3 SN:3526 August 25, 2006

Deviation from Isotropy in HSL

Error (ϕ, ϑ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

5. Uncertainty Analysis

DASY4 Uncertainty Budget
According to IEEE P1528 [1]

Error Description	Uncertainty value	Prob. Dist.	Div.	(c_i) 1g	(c_i) 10g	Std. Unc. (1g)	Std. Unc. (10g)	(v_i) v_{eff}
Measurement System								
Probe Calibration	±4.8 %	N	1	1	1	±4.8 %	±4.8 %	∞
Axial Isotropy	±4.7 %	R	$\sqrt{3}$	0.7	0.7	±1.9 %	±1.9 %	∞
Hemispherical Isotropy	±9.6 %	R	$\sqrt{3}$	0.7	0.7	±3.9 %	±3.9 %	∞
Boundary Effects	±1.0 %	R	$\sqrt{3}$	1	1	±0.6 %	±0.6 %	∞
Linearity	±4.7 %	R	$\sqrt{3}$	1	1	±2.7 %	±2.7 %	∞
System Detection Limits	±1.0 %	R	$\sqrt{3}$	1	1	±0.6 %	±0.6 %	∞
Readout Electronics	±1.0 %	N	1	1	1	±1.0 %	±1.0 %	∞
Response Time	±0.8 %	R	$\sqrt{3}$	1	1	±0.5 %	±0.5 %	∞
Integration Time	±2.6 %	R	$\sqrt{3}$	1	1	±1.5 %	±1.5 %	∞
RF Ambient Conditions	±3.0 %	R	$\sqrt{3}$	1	1	±1.7 %	±1.7 %	∞
Probe Positioner	±0.4 %	R	$\sqrt{3}$	1	1	±0.2 %	±0.2 %	∞
Probe Positioning	±2.9 %	R	$\sqrt{3}$	1	1	±1.7 %	±1.7 %	∞
Max. SAR Eval.	±1.0 %	R	$\sqrt{3}$	1	1	±0.6 %	±0.6 %	∞
Test Sample Related								
Device Positioning	±2.9 %	N	1	1	1	±2.9 %	±2.9 %	875
Device Holder	±3.6 %	N	1	1	1	±3.6 %	±3.6 %	5
Power Drift	±5.0 %	R	$\sqrt{3}$	1	1	±2.9 %	±2.9 %	∞
Phantom and Setup								
Phantom Uncertainty	±4.0 %	R	$\sqrt{3}$	1	1	±2.3 %	±2.3 %	∞
Liquid Conductivity (target)	±5.0 %	R	$\sqrt{3}$	0.64	0.43	±1.8 %	±1.2 %	∞
Liquid Conductivity (meas.)	±2.5 %	N	1	0.64	0.43	±1.6 %	±1.1 %	∞
Liquid Permittivity (target)	±5.0 %	R	$\sqrt{3}$	0.6	0.49	±1.7 %	±1.4 %	∞
Liquid Permittivity (meas.)	±2.5 %	N	1	0.6	0.49	±1.5 %	±1.2 %	∞
Combined Std. Uncertainty						±10.3 %	±10.0 %	331
Expanded STD Uncertainty						**±20.6 %**	**±20.1 %**	

6. Phantom Description

Schmid & Partner Engineering AG

s p e a g

Zeughausstrasse 43, 8004 Zurich, Switzerland
Phone +41 1 245 9700, Fax +41 1 245 9779
info@speag.com, http://www.speag.com

Certificate of Conformity / First Article Inspection

Item	SAM Twin Phantom V4.0
Type No	QD 000 P40 C
Series No	TP-1150 and higher
Manufacturer	SPEAG Zeughausstrasse 43 CH-8004 Zürich Switzerland

Tests

The series production process used allows the limitation to test of first articles.
Complete tests were made on the pre-series Type No. QD 000 P40 AA, Serial No. TP-1001 and on the series first article Type No. QD 000 P40 BA, Serial No. TP-1006. Certain parameters have been retested using further series items (called samples) or are tested at each item.

Test	Requirement	Details	Units tested
Dimensions	Compliant with the geometry according to the CAD model.	IT'IS CAD File (*)	First article, Samples
Material thickness of shell	Compliant with the requirements according to the standards	2mm +/- 0.2mm in flat and specific areas of head section	First article, Samples, TP-1314 ff.
Material thickness at ERP	Compliant with the requirements according to the standards	6mm +/- 0.2mm at ERP	First article, All items
Material parameters	Dielectric parameters for required frequencies	300 MHz – 6 GHz: Relative permittivity < 5, Loss tangent < 0.05	Material samples
Material resistivity	The material has been tested to be compatible with the liquids defined in the standards if handled and cleaned according to the instructions. Observe technical Note for material compatibility.	DEGMBE based simulating liquids	Pre-series, First article, Material samples
Sagging	Compliant with the requirements according to the standards. Sagging of the flat section when filled with tissue simulating liquid.	< 1% typical < 0.8% if filled with 155mm of HSL900 and without DUT below	Prototypes, Sample testing

Standards

[1] CENELEC EN 50361
[2] IEEE Std 1528-2003
[3] IEC 62209 Part I
[4] FCC OET Bulletin 65, Supplement C, Edition 01-01
(*) The IT'IS CAD file is derived from [2] and is also within the tolerance requirements of the shapes of the other documents.

Conformity

Based on the sample tests above, we certify that this item is in compliance with the uncertainty requirements of SAR measurements specified in standards [1] to [4].

Date 07.07.2005

Signature / Stamp

s p e a g
Schmid & Partner Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland
Phone +41 1 245 9700, Fax +41 1 245 9779
info@speag.com, http://www.speag.com

7. System Validation from Original equipment supplier

DASY4 Validation Report for Body TSL

Date/Time: 12.02.2007 14:24:23

Test Laboratory: SPEAG, Zurich, Switzerland

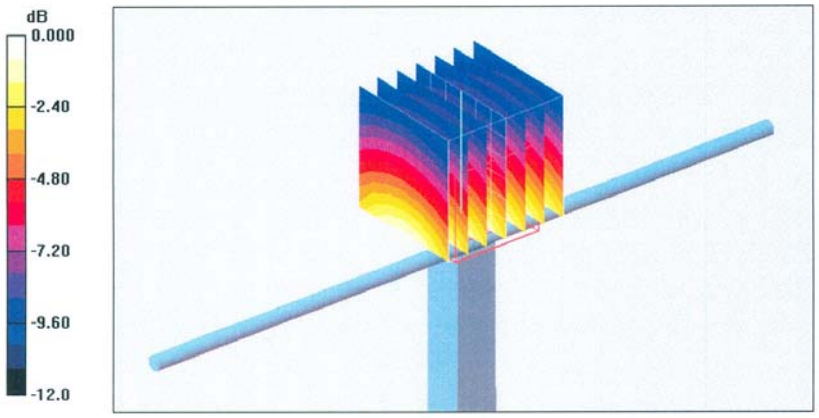
DUT: Dipole 900 MHz; Type: D900V2; Serial: D900V2 - SN:178

Communication System: CW; Frequency: 900 MHz;Duty Cycle: 1:1
Medium: MSL900;
Medium parameters used: f = 900 MHz; σ = 1.04 mho/m; ε_r = 52.4; ρ = 1000 kg/m^3
Phantom section: Flat Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ET3DV6 - SN1507 (HF); ConvF(5.8, 5.8, 5.8); Calibrated: 19.10.2006
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn601; Calibrated: 30.01.2007
- Phantom: Flat Phantom 4.9L; Type: QD000P49AA; ;
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Pin=250mW/Zoom Scan (7x7x7)/Cube 0:
Measurement grid: dx=5mm, dy=5mm, dz=5mm
Reference Value = 55.9 V/m; Power Drift = 0.018 dB
Peak SAR (extrapolated) = 3.80 W/kg
SAR(1 g) = 2.69 mW/g; SAR(10 g) = 1.76 mW/g
Maximum value of SAR (measured) = 2.92 mW/g



0 dB = 2.92mW/g

DASY4 Validation Report for Body TSL

Date/Time: 20.03.2007 15:34:07

Test Laboratory: SPEAG, Zurich, Switzerland

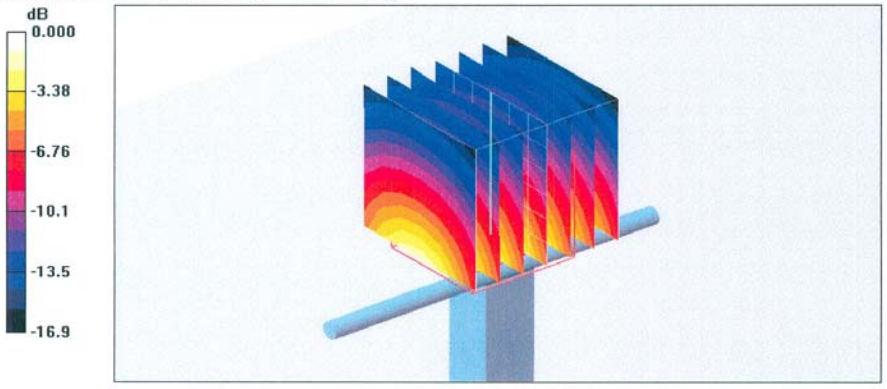
DUT: Dipole 1900 MHz; Type: D1900V2; Serial: D1900V2 - SN:5d027

Communication System: CW; Frequency: 1900 MHz;Duty Cycle: 1:1
Medium: MSL U10 BB;
Medium parameters used: f = 1900 MHz; σ = 1.58 mho/m; ε_r = 51.9; ρ = 1000 kg/m^3
Phantom section: Flat Section
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ET3DV6 - SN1507 (HF); ConvF(4.43, 4.43, 4.43); Calibrated: 19.10.2006
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn601; Calibrated: 30.01.2007
- Phantom: Flat Phantom 5.0 (back); Type: QD000P50AA; ;
- Measurement SW: DASY4, V4.7 Build 53; Postprocessing SW: SEMCAD, V1.8 Build 172

Pin = 250 mW; d = 10 mm/Zoom Scan (7x7x7)/Cube 0:
Measurement grid: dx=5mm, dy=5mm, dz=5mm
Reference Value = 90.5 V/m; Power Drift = -0.010 dB
Peak SAR (extrapolated) = 16.2 W/kg
SAR(1 g) = 9.67 mW/g; SAR(10 g) = 5.16 mW/g
Maximum value of SAR (measured) = 10.9 mW/g



0 dB = 10.9mW/g